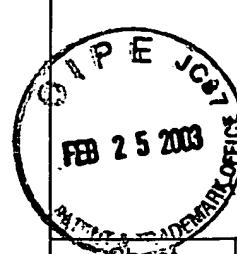


INFORMATION DISCLOSURE STATEMENT BY APPLICANT Form PTO-1449 (Modified) (Use several sheets if necessary)				COMPLETE IF KNOWN	
FEB 25 2003 U.S. PATENT AND TRADEMARK OFFICE P.E. REC'D	Application Number	09/651,779			
	Confirmation Number	2448			
	Filing Date	August 30, 2000			
	First Named Inventor	Scott E. Moore			
	Group Art Unit	3723			
	Examiner Name	Dung V. Nguyen			
Sheet	1	of	4	Attorney Docket No.	108298515US

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Examiner Initials*	Cite No.	U.S. Patent or Application NUMBER		Name of Patentee or Inventor of Cited Document	Date of Publication or Filing Date of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Kind Code (if known)				
DVN	AA✓	U.S. Application No. 09/651,808 (Atty. Docket No. 4373US)		Chopra et al.	Filed 08/30/2000	
	AB✓	U.S. Application No. 09/653,392 (Atty. Docket No. MTI-31044)		Chopra et al.	Filed 08/31/2000	
	AC✓	U.S. Application No. 10/090,869 (Atty. Docket No. 10829.8544US)		Moore et al.	Filed 03/04/2002	
	AD✓	U.S. Application No. 10/230,463 (Atty. Docket No. 10829.8672US)		Lee et al.	Filed 08/29/2002	
	AE✓	U.S. Application No. 10/230,602 (Atty. Docket No. 10829.8674US)		Chopra	Filed 08/29/2002	
	AF✓	U.S. Application No. 10/230,628 (Atty. Docket No. 10829.8673US)		Lee et al.	Filed 08/29/2002	
	AG✓	U.S. Application No. 10/230,970 (Atty. Docket No. 10829.8515US6)		Lee et al.	Filed 08/29/2002	TECHNOLOGY CENTER R3700 MAR 04 2003
	AH✓	U.S. Application No. 10/230,972 (Atty. Docket No. 10829.8515US7)		Lee et al.	Filed 08/29/2002	
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Attorney Docket No.	108298515US

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of

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EXAMINER	DATE CONSIDERED
Dung V. Nguyen	4-21-2003

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Sheet	3	of	4	Attorney Docket No.	108298515US

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		NUMBER	Kind Code (if known)			
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		Office	NUMBER	Kind Code (if known)				
DVN	BX/	WO	00/26443		Talieh	05/11/2000		
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	BZ/	WO	00/32356		Talieh	06/08/2000		
	CA/	WO	00/59008		Talieh	10/05/2000		
↓	CB/	WO	00/59682		Talieh	10/12/2000		

OTHER PRIOR ART-NON PATENT LITERATURE DOCUMENTS							
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume issue number(s), publisher, city and/or country where published.					T
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	CH✓	Micro Photonics, Inc., "CSM Nano Hardness Tester", http://www.microphotonics.com/nht.html , 7/29/2002, 6 pages.		
	CI✓	PhysicsWorld – Table of Contents, PhysicsWeb, "Hard Materials", http://physicsweb.org/box/world/11/1/11/world-11-1-11-1 , 7/29/2002, 1 page.		

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